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### What is "[Embedded - Microcontrollers](#)"?

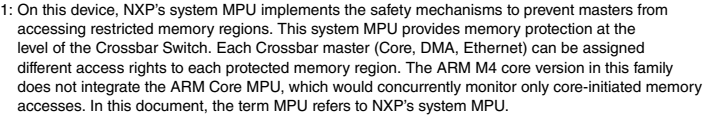
"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Obsolete
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	112MHz
Connectivity	CANbus, FlexIO, I <sup>2</sup> C, LINbus, SPI, UART/USART
Peripherals	POR, PWM, WDT
Number of I/O	58
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b SAR; D/A1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/nxp-semiconductors/fs32k142uft0vlht">https://www.e-xfl.com/product-detail/nxp-semiconductors/fs32k142uft0vlht</a>

Following figures show superset high level architecture block diagrams of S32K14x series and S32K11x series respectively. Other devices within the family have a subset of the features. See [Feature comparison](#) for chip specific values.



2: For the device-specific sizes, see the "On-chip SRAM sizes" table in the "Memories and Memory Interfaces" chapter of the S32K14x Series Reference Manual.

Key:

Device architectural IP  
on all S32K devices

Peripherals present  
on all S32K devices

Peripherals present  
on selected S32K devices  
(see the "Feature Comparison"  
section in the RM)

**Figure 1. High-level architecture diagram for the S32K14x family**

## 3 Ordering parts

### 3.1 Determining valid orderable parts

To determine the orderable part numbers for this device, go to [www.nxp.com](http://www.nxp.com) and perform a part number search. Additionally see the attachment *S32K\_Part\_Numbers.xlsx*.

#### NOTE

Not all part number combinations exist

## 3.2 Ordering information

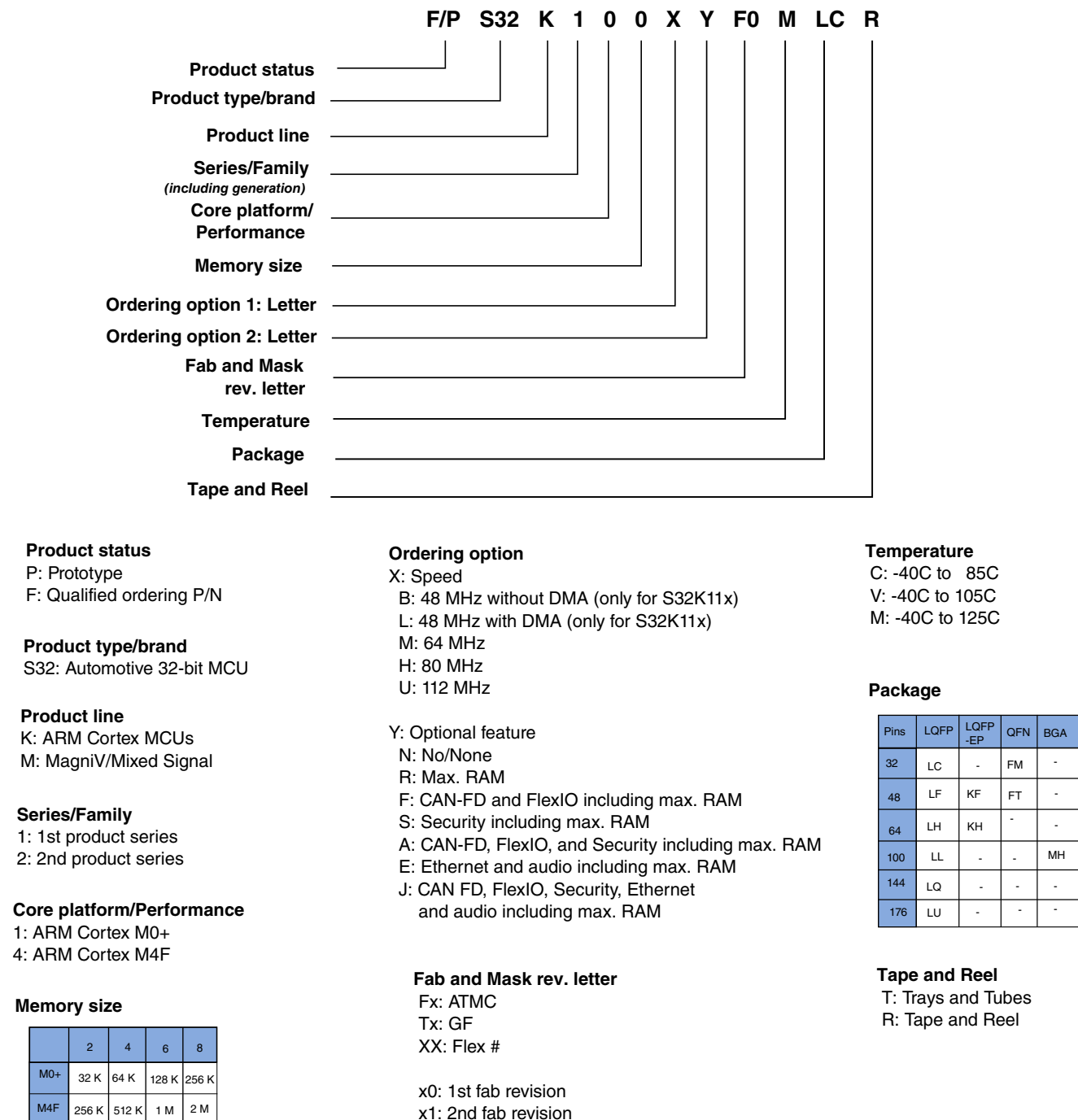


Figure 4. Ordering information

## General

$T_J$  (Junction temperature)=125 °C. Assumes  $T_A$ =105 °C for HSRUN mode

- Assumes maximum  $\theta_{JA}$  for 2s2p board. See [Thermal characteristics](#)

8. 60 seconds lifetime; device in reset (no outputs enabled/toggling)

## 4.2 Voltage and current operating requirements

### NOTE

Full functionality/specifications cannot be guaranteed when voltage drops below 2.7 V.

**Table 2. Voltage and current operating requirements 1**

Symbol	Description	Min.	Max.	Unit	Notes
$V_{DD}$ <sup>2</sup>	Supply voltage	2.7 <sup>3</sup>	5.5	V	4
$V_{DD\_OFF}$	Voltage allowed to be developed on $V_{DD}$ pin when it is not powered from any external power supply source.	0	0.1	V	
$V_{DDA}$	Analog supply voltage	2.7	5.5	V	4
$V_{DD} - V_{DDA}$	$V_{DD}$ -to- $V_{DDA}$ differential voltage	-0.1	0.1	V	
$V_{REFH}$	ADC reference voltage high	2.7	$V_{DDA} + 0.1$	V	5
$V_{REFL}$	ADC reference voltage low	-0.1	0.1	V	
$V_{ODPU}$	Open drain pullup voltage level	$V_{DD}$	$V_{DD}$	V	6
$I_{INJPAD\_DC\_OP}$ <sup>7</sup>	Continuous DC input current (positive / negative) that can be injected into an I/O pin	-3	+3	mA	
$I_{INJSUM\_DC\_OP}$	Continuous total DC input current that can be injected across all I/O pins such that there's no degradation in accuracy of analog modules: ADC and ACMP (See section <a href="#">Analog Modules</a> )	—	30	mA	

- Typical conditions assumes  $V_{DD} = V_{DDA} = V_{REFH} = 5$  V, temperature = 25 °C and typical silicon process unless otherwise stated.
- As  $V_{DD}$  varies between the minimum value and the absolute maximum value the analog characteristics of the I/O and the ADC will both change. See section [I/O parameters](#) and [ADC electrical specifications](#) respectively for details.
- S32K148 will operate from 2.7 V when executing from internal FIRC. When the PLL is engaged S32K148 is guaranteed to operate from 2.97 V. All other S32K family devices operate from 2.7 V in all modes.
- $V_{DD}$  and  $V_{DDA}$  must be shorted to a common source on PCB. Appropriate decoupling capacitors to be used to filter noise on the supplies. See application note [AN5032](#) for reference supply design for SAR ADC.
- $V_{REFH}$  should always be equal to or less than  $V_{DDA} + 0.1$  V and  $V_{DD} + 0.1$  V
- Open drain outputs must be pulled to  $V_{DD}$ .
- When input pad voltage levels are close to  $V_{DD}$  or  $V_{SS}$ , practically no current injection is possible.

## 4.4 Power and ground pins

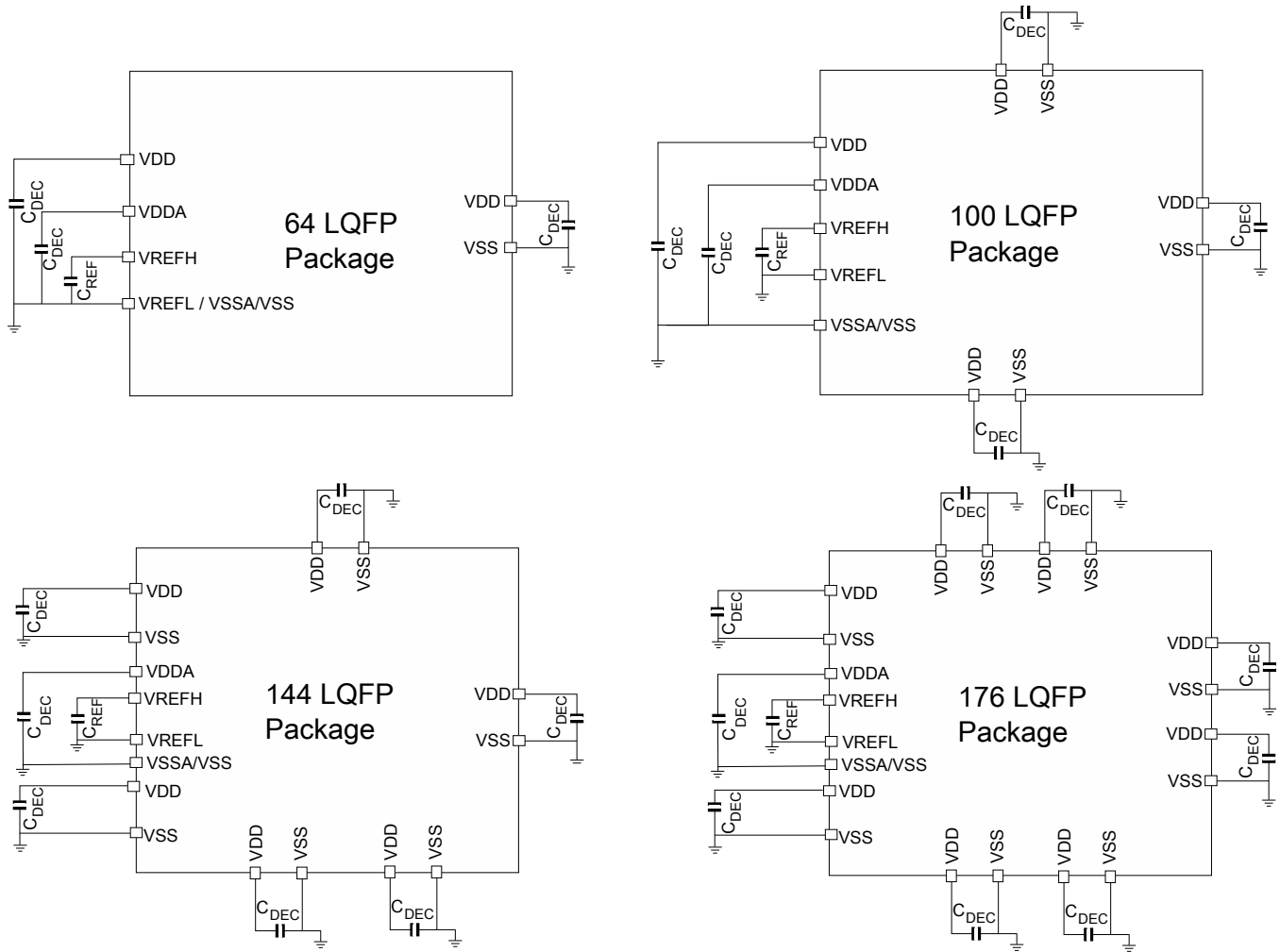


Figure 5. Pinout decoupling

Table 4. Supplies decoupling capacitors 1, 2

Symbol	Description	Min. <sup>3</sup>	Typ.	Max.	Unit
$C_{REF}^{4, 5}$	ADC reference high decoupling capacitance	70	100	—	nF
$C_{DEC}^{5, 6, 7}$	Recommended decoupling capacitance	70	100	—	nF

- $V_{DD}$  and  $V_{DDA}$  must be shorted to a common source on PCB. Appropriate decoupling capacitors to be used to filter noise on the supplies. See application note AN5032 for reference supply design for SAR ADC. All  $V_{SS}$  pins should be connected to common ground at the PCB level.
- All decoupling capacitors must be low ESR ceramic capacitors (for example X7R type).
- Minimum recommendation is after considering component aging and tolerance.
- For improved performance, it is recommended to use 10  $\mu$ F, 0.1  $\mu$ F and 1 nF capacitors in parallel.
- All decoupling capacitors should be placed as close as possible to the corresponding supply and ground pins.
- Contact your local Field Applications Engineer for details on best analog routing practices.
- The filtering used for decoupling the device supplies must comply with the following best practices rules:
  - The protection/decoupling capacitors must be on the path of the trace connected to that component.

**Table 5.  $V_{DD}$  supply LVR, LVD and POR operating requirements (continued)**

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
$V_{LVD}$	Falling low-voltage detect threshold	2.8	2.875	3	V	
$V_{LVD\_HYST}$	LVD hysteresis	—	50	—	mV	1
$V_{LVW}$	Falling low-voltage warning threshold	4.19	4.305	4.5	V	
$V_{LVW\_HYST}$	LVW hysteresis	—	75	—	mV	1
$V_{BG}$	Bandgap voltage reference	0.97	1.00	1.03	V	

1. Rising threshold is the sum of falling threshold and hysteresis voltage.

## 4.6 Power mode transition operating behaviors

All specifications in the following table assume this clock configuration:

- RUN Mode:
  - Clock source: FIRC
  - SYS\_CLK/CORE\_CLK = 48 MHz
  - BUS\_CLK = 48 MHz
  - FLASH\_CLK = 24 MHz
- HSRUN Mode:
  - Clock source: SPLL
  - SYS\_CLK/CORE\_CLK = 112 MHz
  - BUS\_CLK = 56 MHz
  - FLASH\_CLK = 28 MHz
- VLPR Mode:
  - Clock source: SIRC
  - SYS\_CLK/CORE\_CLK = 4 MHz
  - BUS\_CLK = 4 MHz
  - FLASH\_CLK = 1 MHz
- STOP1/STOP2 Mode:
  - Clock source: FIRC
  - SYS\_CLK/CORE\_CLK = 48 MHz
  - BUS\_CLK = 48 MHz
  - FLASH\_CLK = 24 MHz
- VLPS Mode: All clock sources disabled.

**Table 6. Power mode transition operating behaviors**

Symbol	Description	Min.	Typ.	Max.	Unit
$t_{POR}$	After a POR event, amount of time from the point $V_{DD}$ reaches 2.7 V to execution of the first instruction across the operating temperature range of the chip.	—	325	—	$\mu$ s

Table continues on the next page...

### 4.7.1 Modes configuration

Attached *S32K1xx\_Power\_Modes\_Configuration.xlsx* details the modes used in gathering the power consumption data stated in the above table [Table 7](#). For full functionality refer to table: Module operation in available low power modes of the *Reference Manual*.

## 4.8 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
$V_{\text{HBM}}$	Electrostatic discharge voltage, human body model	– 4000	4000	V	<a href="#">1</a>
$V_{\text{CDM}}$	Electrostatic discharge voltage, charged-device model				<a href="#">2</a>
	All pins except the corner pins	– 500	500	V	
	Corner pins only	– 750	750	V	
$I_{\text{LAT}}$	Latch-up current at ambient temperature of 125 °C	– 100	100	mA	<a href="#">3</a>

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.
3. Determined according to JEDEC Standard JESD78, *IC Latch-Up Test*.

## 4.9 EMC radiated emissions operating behaviors

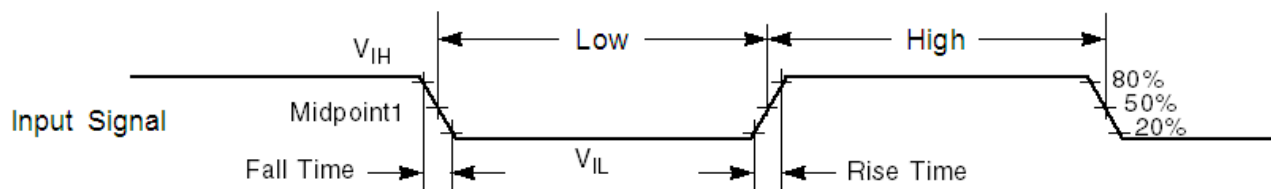
EMC measurements to IC-level IEC standards are available from NXP on request.

# 5 I/O parameters

## 5.1 AC electrical characteristics

Unless otherwise specified, propagation delays are measured from the 50% to the 50% point, and rise and fall times are measured at the 20% and 80% points, as shown in the following figure.





The midpoint is  $V_{IL} + (V_{IH} - V_{IL})/2$ .

**Figure 7. Input signal measurement reference**

## 5.2 General AC specifications

These general purpose specifications apply to all signals configured for GPIO, UART, and timers.

**Table 8. General switching specifications**

Symbol	Description	Min.	Max.	Unit	Notes
	GPIO pin interrupt pulse width (digital glitch filter disabled) — Synchronous path	1.5	—	Bus clock cycles	1, 2
	GPIO pin interrupt pulse width (digital glitch filter disabled, passive filter disabled) — Asynchronous path	50	—	ns	3
WFRST	RESET input filtered pulse	—	100	ns	4
WFRST	RESET input not filtered pulse	100	—	ns	

1. This is the minimum pulse width that is guaranteed to pass through the pin synchronization circuitry. Shorter pulses may or may not be recognized. In Stop and VLPS modes, the synchronizer is bypassed so shorter pulses can be recognized in that case.
2. The greater of synchronous and asynchronous timing must be met.
3. These pins do not have a passive filter on the inputs. This is the shortest pulse width that is guaranteed to be recognized.
4. Minimum length of  $\overline{\text{RESET}}$  pulse, guaranteed not to be filtered by the internal filter.

## 5.3 DC electrical specifications at 3.3 V Range

**Table 9. DC electrical specifications at 3.3 V Range**

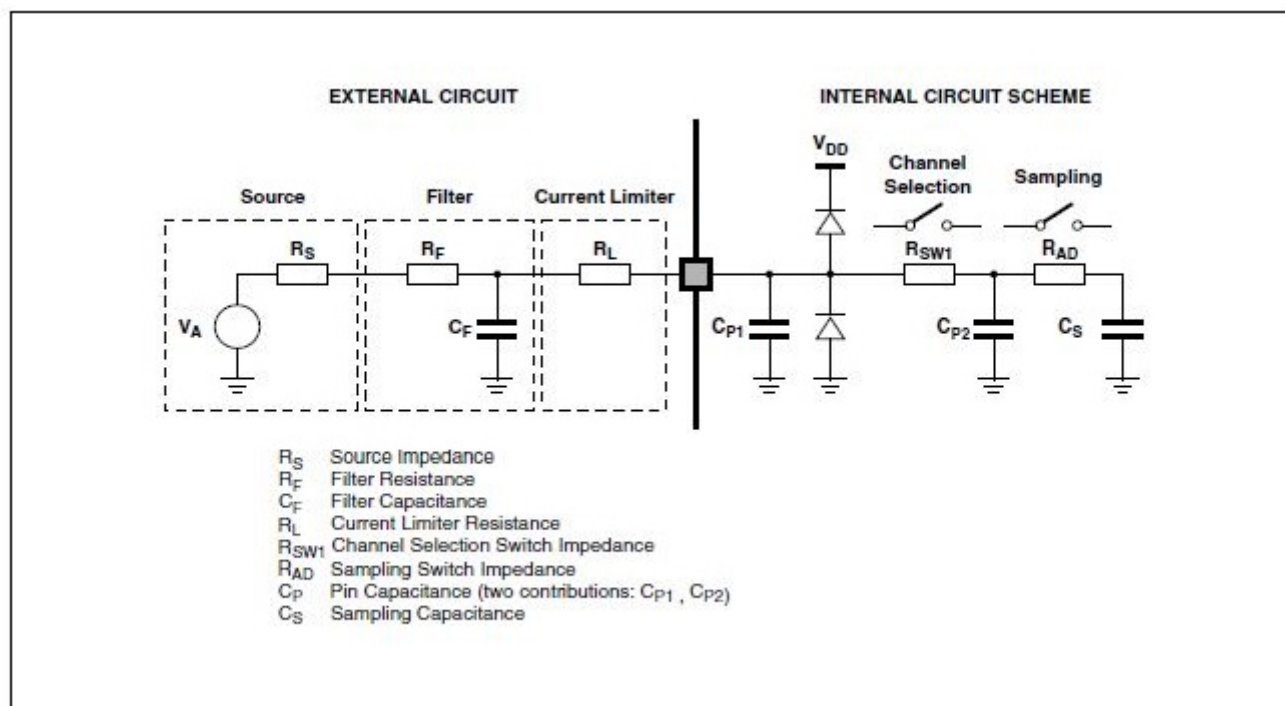
Symbol	Parameter	Value			Unit	Notes
		Min.	Typ.	Max.		
$V_{DD}$	I/O Supply Voltage	2.7	3.3	4	V	1
$V_{ih}$	Input Buffer High Voltage	$0.7 \times V_{DD}$	—	$V_{DD} + 0.3$	V	2
$V_{il}$	Input Buffer Low Voltage	$V_{SS} - 0.3$	—	$0.3 \times V_{DD}$	V	3
$V_{hys}$	Input Buffer Hysteresis	$0.06 \times V_{DD}$	—	—	V	
Ioh_Standard	I/O current source capability measured when pad = ( $V_{DDE} - 0.8$ V)	3.5	—	—	mA	

Table continues on the next page...

**Table 24. 12-bit ADC operating conditions (continued)**

Symbol	Description	Conditions	Min.	Typ. <sup>1</sup>	Max.	Unit	Notes
$C_{P2}$	Analog Bus Capacitance		—	—	4	pF	
$C_S$	Sampling capacitance		—	4	5	pF	
$f_{ADCK}$	ADC conversion clock frequency	Normal usage	2	40	50	MHz	4, 5
$f_{CONV}$	ADC conversion frequency	No ADC hardware averaging. <sup>6</sup> Continuous conversions enabled, subsequent conversion time	46.4	928	1160	Ksps	7, 8
		ADC hardware averaging set to 32. <sup>6</sup> Continuous conversions enabled, subsequent conversion time	1.45	29	36.25	Ksps	7, 8

- Typical values assume  $V_{DDA} = 5\text{ V}$ ,  $\text{Temp} = 25\text{ }^{\circ}\text{C}$ ,  $f_{ADCK} = 40\text{ MHz}$ ,  $R_{AS} = 20\text{ }\Omega$ , and  $C_{AS} = 10\text{ nF}$  unless otherwise stated. Typical values are for reference only, and are not tested in production.
- DC potential difference.
- For packages without dedicated  $V_{REFH}$  and  $V_{REFL}$  pins,  $V_{REFH}$  is internally tied to  $V_{DDA}$ , and  $V_{REFL}$  is internally tied to  $V_{SS}$ . To get maximum performance, reference supply quality should be better than SAR ADC. See application note [AN5032](#) for details.
- Clock and compare cycle need to be set according to the guidelines mentioned in the *Reference Manual*.
- ADC conversion will become less reliable above maximum frequency.
- When using ADC hardware averaging, see the *Reference Manual* to determine the most appropriate setting for AVGS.
- Numbers based on the minimum sampling time of 275 ns.
- For guidelines and examples of conversion rate calculation, see the *Reference Manual* or download the ADC calculator tool.

**Figure 13. ADC input impedance equivalency diagram**

### 6.4.1.2 12-bit ADC electrical characteristics

#### NOTE

ADC performance specifications are documented using a single ADC. For parallel/simultaneous operation of both ADCs, either for sampling the same channel by both ADCs or for sampling different channels by each ADC, some amount of decrease in performance can be expected. Care must be taken to stagger the two ADC conversions, in particular the sample phase, to minimize the impact of simultaneous conversions.

**Table 25. 12-bit ADC characteristics (2.7 V to 3 V) ( $V_{REFH} = V_{DDA}$ ,  $V_{REFL} = V_{SS}$ )**

Symbol	Description	Conditions <sup>1</sup>	Min.	Typ. <sup>2</sup>	Max.	Unit	Notes
$V_{DDA}$	Supply voltage		2.7	—	3	V	
$I_{DDA\_ADC}$	Supply current per ADC		—	0.6	1.5	mA	3
SMPLTS	Sample Time		275	—	Refer to the <i>Reference Manual</i>	ns	
TUE <sup>4</sup>	Total unadjusted error		—	±4	±8	LSB <sup>5</sup>	6, 7, 8, 9
DNL	Differential non-linearity		—	±1.0	—	LSB <sup>5</sup>	6, 7, 8, 9
INL	Integral non-linearity		—	±2.0	—	LSB <sup>5</sup>	6, 7, 8, 9

1. All accuracy numbers assume the ADC is calibrated with  $V_{REFH}=V_{DDA}=V_{DD}$ , with the calibration frequency set to half the ADC clock frequency.
2. Typical values assume  $V_{DDA} = 3$  V, Temp = 25 °C,  $f_{ADCK} = 40$  MHz,  $R_{AS}=20$  Ω, and  $C_{AS}=10$  nF, 100 LQFP package unless otherwise stated.
3. The ADC supply current depends on the ADC conversion rate.
4. Represents total static error, which includes offset and full scale error.
5.  $1 \text{ LSB} = (V_{REFH} - V_{REFL})/2^N$
6. The specifications are with averaging and in standalone mode only. Performance may degrade depending upon device use case scenario. When using ADC averaging, refer to the *Reference Manual* to determine the most appropriate settings for AVGS.
7. For ADC signals adjacent to  $V_{DD}/V_{SS}$  or XTAL/EXTAL or high frequency switching pins, some degradation in the ADC performance may be observed.
8. All values guarantee the performance of the ADC for multiple ADC input channel pins. When using ADC to monitor the internal analog parameters, assume minor degradation.
9. All the parameters in the table are given assuming system clock as the clocking source for ADC.

**Table 26. 12-bit ADC characteristics (3 V to 5.5 V)( $V_{REFH} = V_{DDA}$ ,  $V_{REFL} = V_{SS}$ )**

Symbol	Description	Conditions <sup>1</sup>	Min.	Typ. <sup>2</sup>	Max.	Unit	Notes
$V_{DDA}$	Supply voltage		3	—	5.5	V	
$I_{DDA\_ADC}$	Supply current per ADC		—	1	2.1	mA	3
SMPLTS	Sample Time		275	—	Refer to the <i>Reference Manual</i>	ns	

Table continues on the next page...

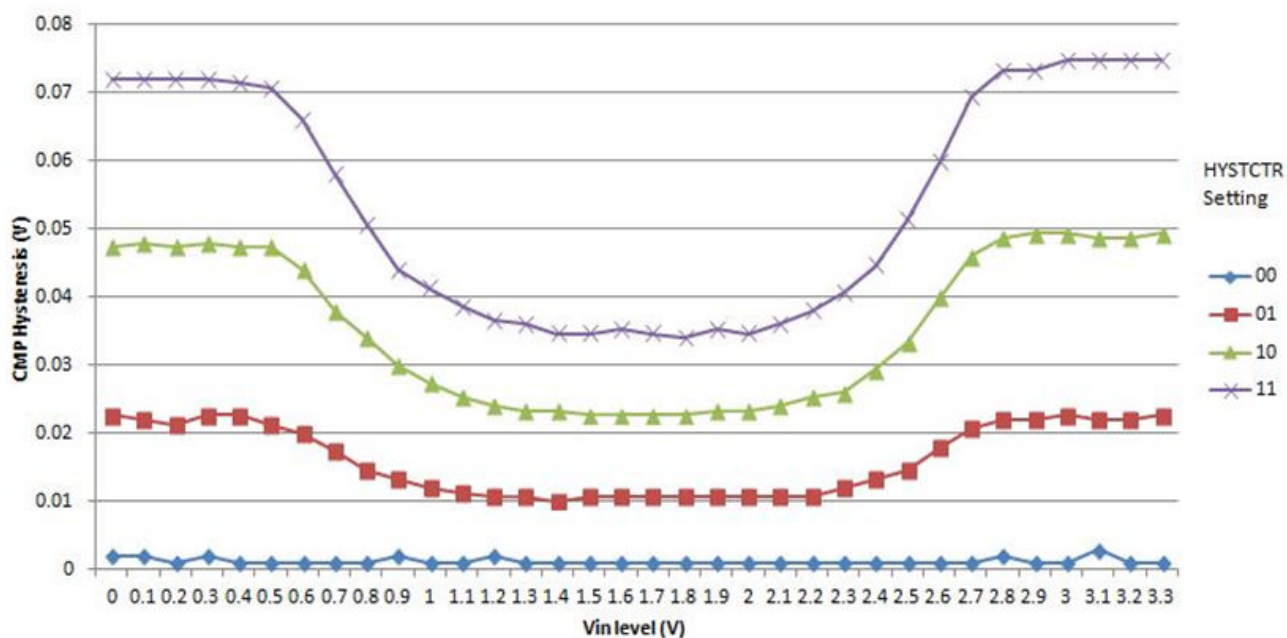


Figure 15. Typical hysteresis vs. Vin level (VDDA = 3.3 V, PMODE = 1)

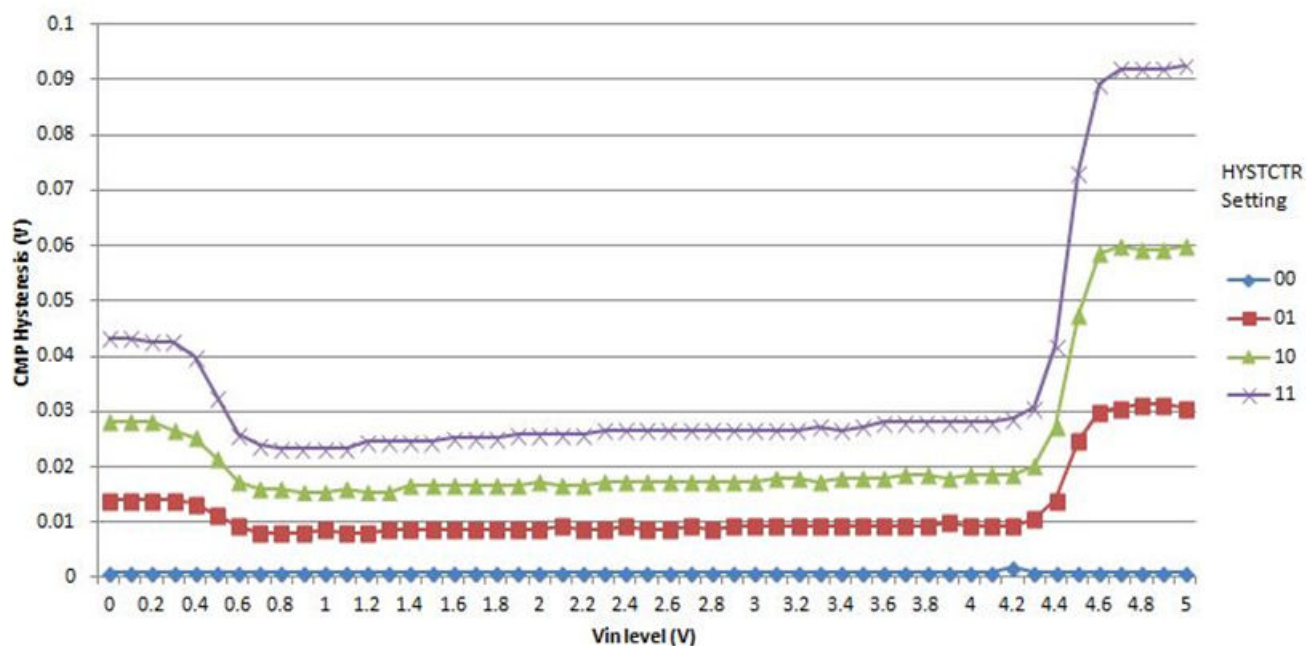
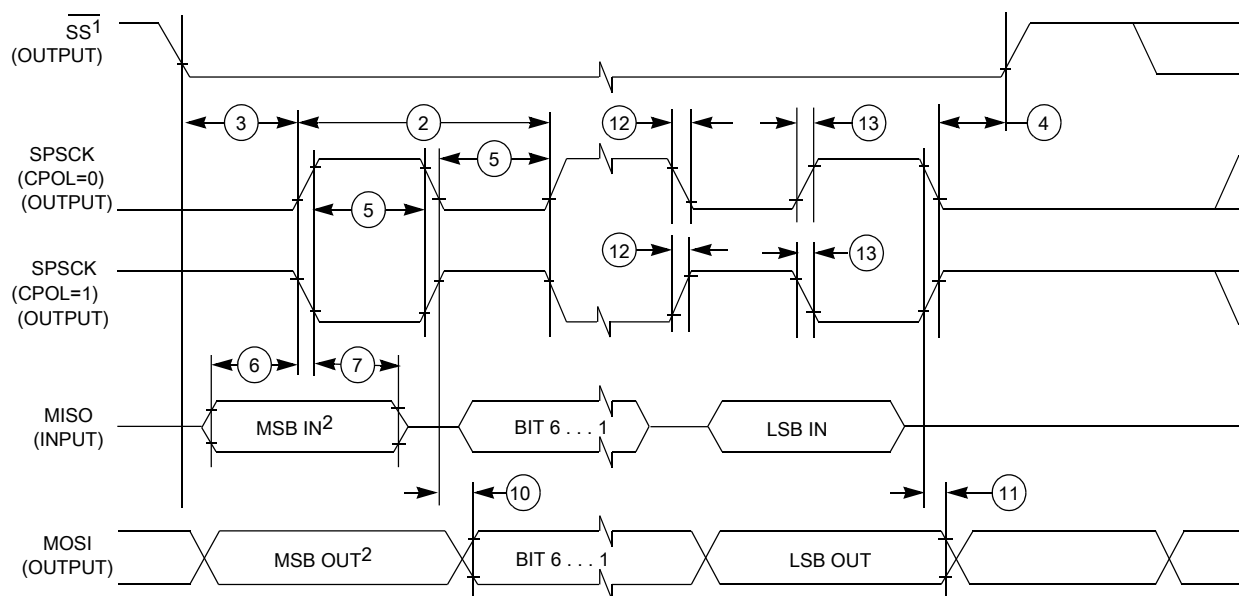
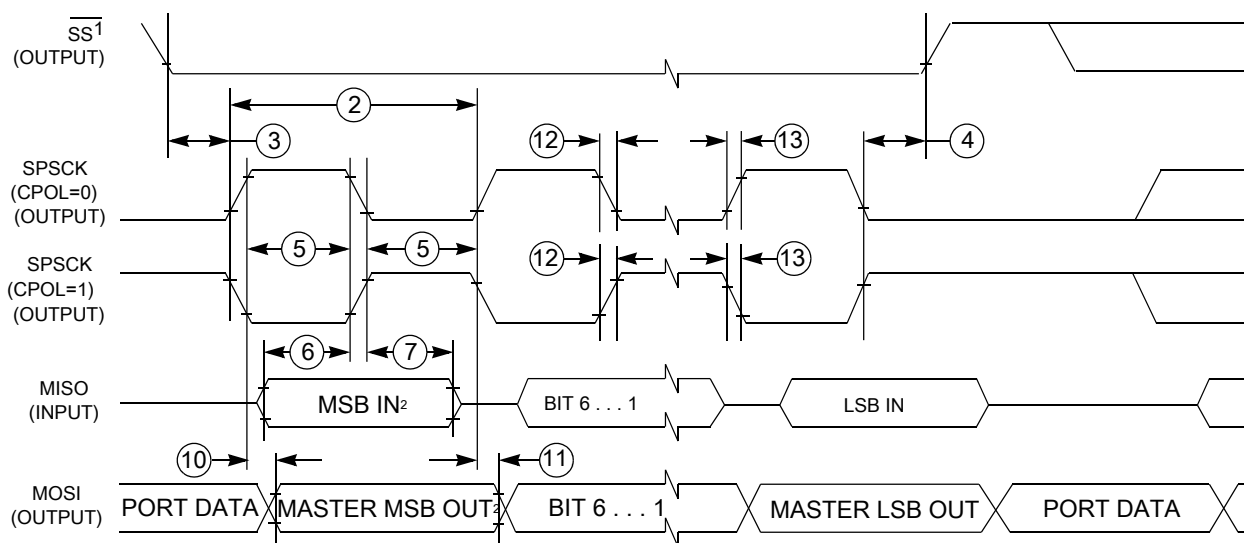


Figure 16. Typical hysteresis vs. Vin level (VDDA = 5 V, PMODE = 0)



1. If configured as an output.
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

**Figure 18. LPSPI master mode timing (CPHA = 0)**



1. If configured as output
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

**Figure 19. LPSPI master mode timing (CPHA = 1)**

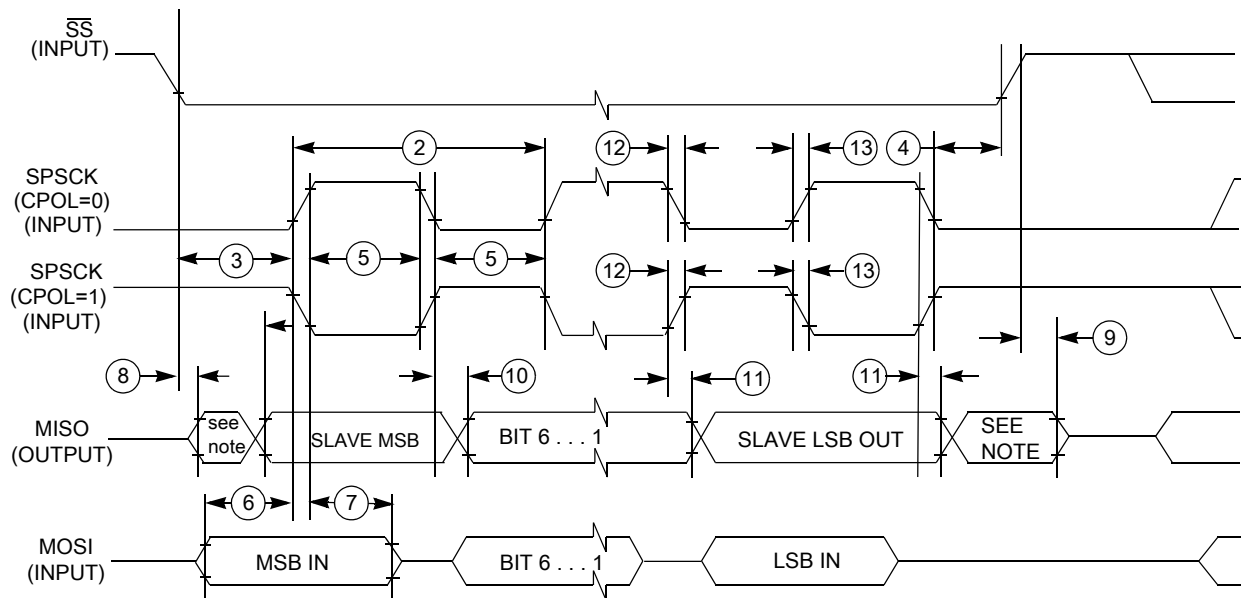


Figure 20. LPSPI slave mode timing (CPHA = 0)

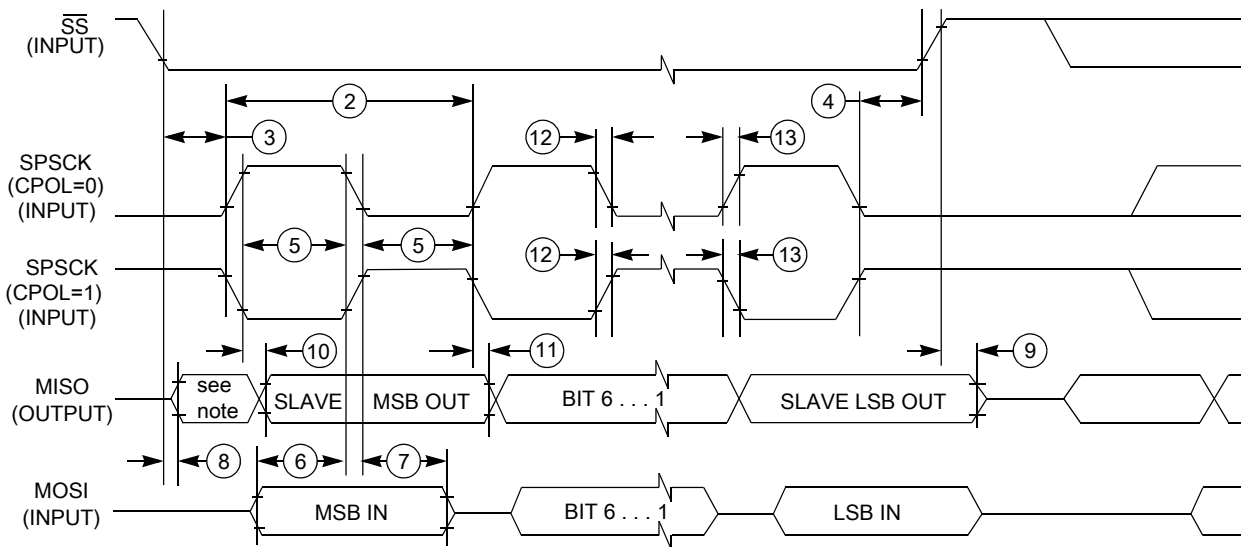


Figure 21. LPSPI slave mode timing (CPHA = 1)

### 6.5.3 LPI2C electrical specifications

See [General AC specifications](#) for LPI2C specifications.

For supported baud rate see section 'Chip-specific LPI2C information' of the *Reference Manual*.

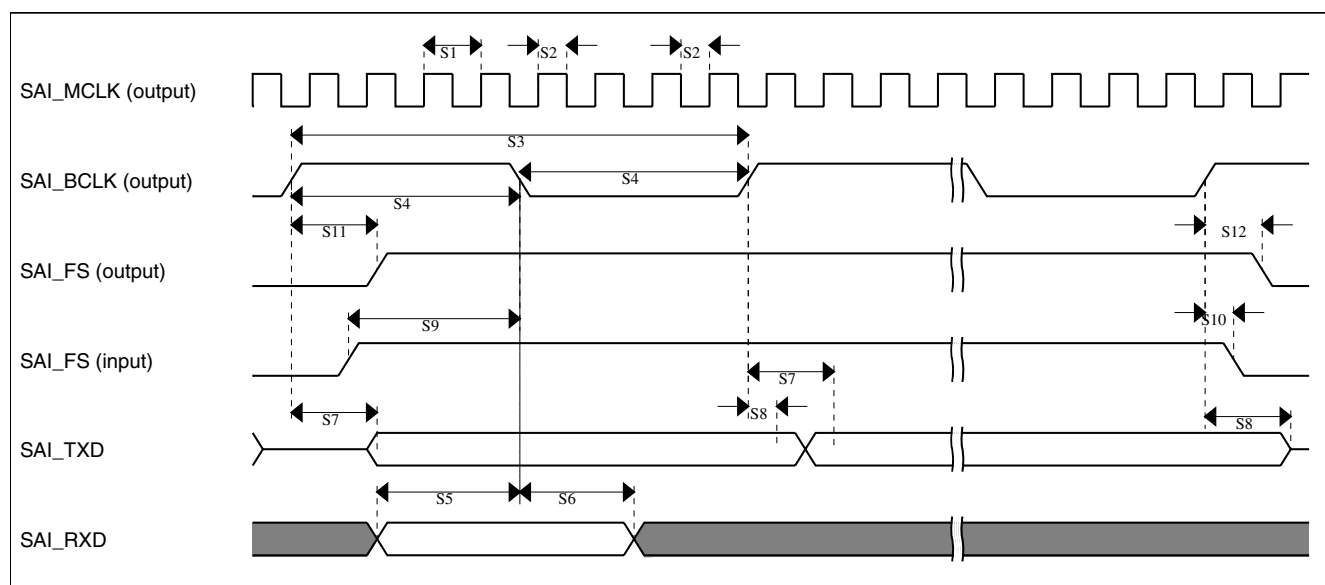


Figure 22. SAI Timing — Master modes

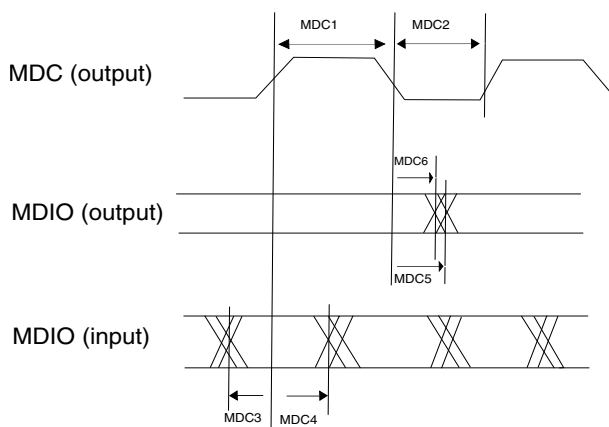
Table 31. Slave mode timing specifications

Symbol	Description	Min.	Max.	Unit
—	Operating voltage	2.97	3.6	V
S13	SAI_BCLK cycle time (input)	80	—	ns
S14 <sup>1</sup>	SAI_BCLK pulse width high/low (input)	45%	55%	BCLK period
S15	SAI_RXD input setup before SAI_BCLK	8	—	ns
S16	SAI_RXD input hold after SAI_BCLK	2	—	ns
S17	SAI_BCLK to SAI_TXD output valid	—	28	ns
S18	SAI_BCLK to SAI_TXD output invalid	0	—	ns
S19	SAI_FS input setup before SAI_BCLK	8	—	ns
S20	SAI_FS input hold after SAI_BCLK	2	—	ns
S21	SAI_BCLK to SAI_FS output valid	—	28	ns
S22	SAI_BCLK to SAI_FS output invalid	0	—	ns

1. The slave mode parameters (S15 - S22) assume 50% duty cycle on SAI\_BCLK input. Any change in SAI\_BCLK duty cycle input must be taken care during the board design or by the master timing.

**Table 34. MDIO timing specifications (continued)**

Symbol	Description	Min.	Max.	Unit
MDC1	MDC pulse width high	40%	60%	MDC period
MDC2	MDC pulse width low	40%	60%	MDC period
MDC3	MDIO (input) to MDC rising edge setup	25	—	ns
MDC4	MDIO (input) to MDC rising edge hold	0	—	ns
MDC5	MDC falling edge to MDIO output valid (maximum propagation delay)	—	25	ns
MDC6	MDC falling edge to MDIO output invalid (minimum propagation delay)	-10	—	ns

**Figure 28. MII/RMII serial management channel timing diagram**

### 6.5.7 Clockout frequency

Maximum supported clock out frequency for this device is 20 MHz

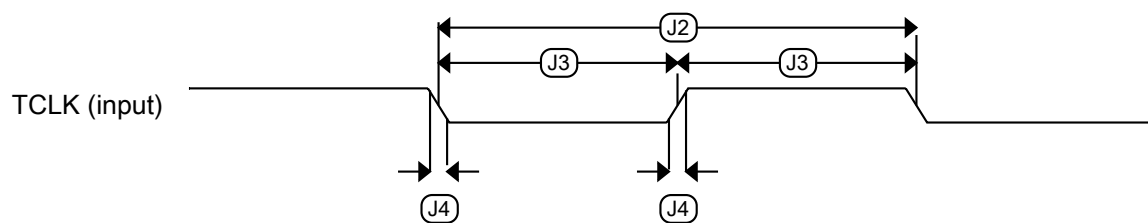
## 6.6 Debug modules

### 6.6.1 SWD electrical specifications

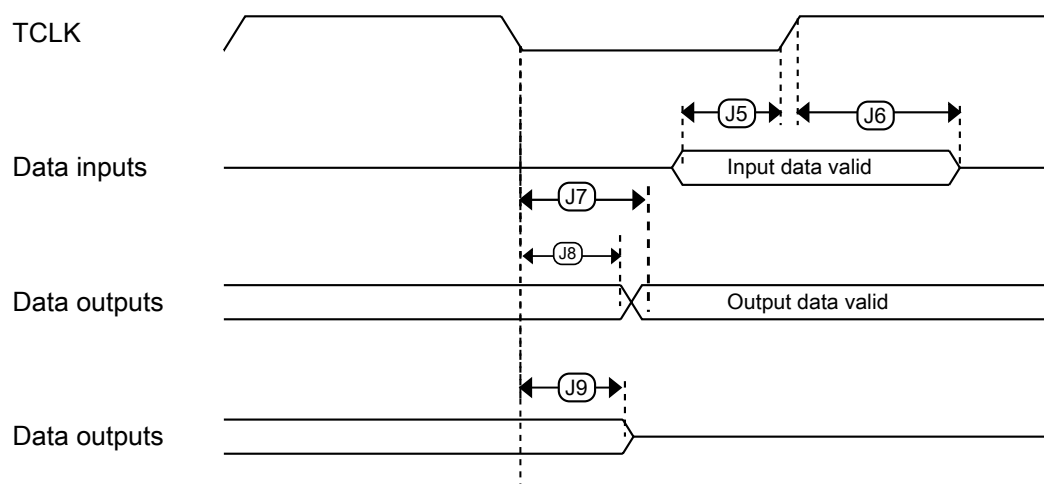


Table 35. SWD electrical specifications

Symbol	Description	Run Mode				HSRUN Mode				VLPR Mode				Unit
		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
S1	SWD_CLK frequency of operation	-	25	-	25	-	25	-	25	-	10	-	10	MHz
S2	SWD_CLK cycle period	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	ns
S3	SWD_CLK clock pulse width	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	ns
S4	SWD_CLK rise and fall times	-	1	-	1	-	1	-	1	-	1	-	1	ns
S9	SWD_DIO input data setup time to SWD_CLK rise	4	-	4	-	4	-	4	-	16	-	16	-	ns
S10	SWD_DIO input data hold time after SWD_CLK rise	3	-	3	-	3	-	3	-	10	-	10	-	ns
S11	SWD_CLK high to SWD_DIO data valid	-	28	-	38	-	28	-	38	-	70	-	77	ns
S12	SWD_CLK high to SWD_DIO high-Z	-	28	-	38	-	28	-	38	-	70	-	77	ns
S13	SWD_CLK high to SWD_DIO data invalid	0	-	0	-	0	-	0	-	0	-	0	-	ns



**Figure 32. Test clock input timing**



**Figure 33. Boundary scan (JTAG) timing**

**Table 38. Thermal characteristics for the 64/100/144/176-pin LQFP package (continued)**

Rating	Conditions	Symbol	Packages	Values					Unit
				S32K11x	S32K142	S32K144	S32K146	S32K148	
Thermal resistance, Junction to Case <sup>5</sup>	—	$R_{\theta JC}$	64	TBD	13	12	11	NA	°C/W
			100	TBD	13	12	11	NA	°C/W
			144	TBD	NA	NA	12	9	°C/W
			176	TBD	NA	NA	NA	9	°C/W
Thermal resistance, Junction to Package Top <sup>6</sup>	Natural Convection	$\psi_{JT}$	64	TBD	2	2	2	NA	°C/W
			100	TBD	2	2	2	NA	°C/W
			144	TBD	NA	NA	2	1	°C/W
			176	TBD	NA	NA	NA	1	°C/W

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with natural convection for horizontally oriented board. Board meets JESD51-9 specification for 1s or 2s2p board, respectively.
3. Per JEDEC JESD51-6 with forced convection for horizontally oriented board. Board meets JESD51-9 specification for 1s or 2s2p board, respectively.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

Table 40. Revision History (continued)

Rev. No.	Date	Substantial Changes
		<ul style="list-style-type: none"> <li>Updated values for <math>V_{REFH}</math> and <math>V_{REFL}</math> to add reference to the section "voltage and current operating requirements" for Min and Max values</li> <li>Updated footnote to Typ.</li> <li>Removed footnote from RAS Analog source resistance</li> <li>Updated figure: ADC input impedance equivalency diagram</li> <li>In table: <a href="#">12-bit ADC characteristics (2.7 V to 3 V)</a> (<math>V_{REFH} = V_{DDA}</math>, <math>V_{REFL} = V_{SS}</math>) <ul style="list-style-type: none"> <li>Removed rows for <math>V_{TEMP\_S}</math> and <math>V_{TEMP25}</math></li> <li>Updated footnote to Typ.</li> </ul> </li> <li>In table: <a href="#">12-bit ADC characteristics (3 V to 5.5 V)</a> (<math>V_{REFH} = V_{DDA}</math>, <math>V_{REFL} = V_{SS}</math>) <ul style="list-style-type: none"> <li>Removed rows for <math>V_{TEMP\_S}</math> and <math>V_{TEMP25}</math></li> <li>Removed number for TUE</li> <li>Updated footnote to Typ.</li> </ul> </li> <li>In table: <a href="#">Comparator with 8-bit DAC electrical specifications</a> <ul style="list-style-type: none"> <li>Updated Typ. of <math>I_{DDL5}</math> Supply current, Low-speed mode</li> <li>Updated Typ. of <math>t_{DLSB}</math> Propagation delay, Low-speed mode</li> <li>Updated Typ. of <math>t_{DHSS}</math> Propagation delay, High-speed mode</li> <li>Updated <math>t_{DLSS}</math> Propagation delay</li> <li>Added row for <math>t_{DDAC}</math> Initialization and switching settling time</li> <li>Updated footnote</li> </ul> </li> <li>Updated section <a href="#">LPSPi electrical specifications</a></li> <li>Added section: <a href="#">SAI electrical specifications</a></li> <li>Updated section: <a href="#">Ethernet AC specifications</a></li> <li>Added section: <a href="#">Clockout frequency</a></li> <li>Added section: <a href="#">Trace electrical specifications</a></li> <li>Updated table: <a href="#">Table 38</a> : Updated numbers for S32K142 and S32K148</li> <li>Updated table: <a href="#">Table 39</a> : Updated numbers for S32K148</li> <li>Updated Document number for 32-pin QFN in topic <a href="#">Obtaining package dimensions</a></li> </ul>
3	14 March 2017	<ul style="list-style-type: none"> <li>In <a href="#">Table 2</a> <ul style="list-style-type: none"> <li>Updated min. value of <math>V_{DD\_OFF}</math></li> <li>Added parameter <math>I_{INJSUM\_AF}</math></li> </ul> </li> <li>Updated <a href="#">Power mode transition operating behaviors</a></li> <li>Updated <a href="#">Power consumption</a></li> <li>Updated footnote to <math>T_{SPLL\_LOCK}</math> in <a href="#">SPLL electrical specifications</a></li> <li>In <a href="#">12-bit ADC electrical characteristics</a> <ul style="list-style-type: none"> <li>Updated table: 12-bit ADC characteristics (2.7 V to 3 V) (<math>V_{REFH} = V_{DDA}</math>, <math>V_{REFL} = V_{SS}</math>) <ul style="list-style-type: none"> <li>Added typ. value to <math>I_{DDA\_ADC}</math>, TUE, DNL, and INL</li> <li>Added min. value to SMPLTS</li> <li>Removed footnote 'All the parameters in this table ... '</li> </ul> </li> <li>Updated table: 12-bit ADC characteristics (3 V to 5.5 V) (<math>V_{REFH} = V_{DDA}</math>, <math>V_{REFL} = V_{SS}</math>) <ul style="list-style-type: none"> <li>Added typ. value to <math>I_{DDA\_ADC}</math></li> <li>Removed footnote 'All the parameters in this table ... '</li> </ul> </li> </ul> </li> <li>In <a href="#">Table 21</a> updated Max. value of <math>t_{vfykey}</math> to 33 <math>\mu s</math></li> </ul>
4	02 June 2017	<ul style="list-style-type: none"> <li>In section: <a href="#">Block diagram</a>, added block diagram for S32K11x series.</li> <li>Updated figure: <a href="#">S32K1xx product series comparison</a>.</li> <li>In section: <a href="#">Determining valid orderable parts</a> , added reference to attachment <a href="#">S32K_Part_Numbers.xlsx</a>.</li> <li>In section: <a href="#">Ordering information</a> <ul style="list-style-type: none"> <li>Updated figure: Ordering information.</li> </ul> </li> <li>In <a href="#">Table 1</a>,</li> </ul>

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Document Number S32K1XX  
Revision 4, 06/2017

